

## Drafts

- BRS:
- BRS:
- BRS:
- BRS: knall
- BRS: 19.21.23
- BRS: 32with 33

## Pending

## Active

- L1: (250718) (silicid\$4 silica\$4)
- L2: (87757) (crystal near 2 (orient\$4 grow\$4 face\$2 facing state))
- L3: (863839) (polysilicon polycrystalline) silicon
- L4: (866667) gate
- L5: (5752055) (different "same")
- L6: (3305000) (different)
- L7: (895) 2 near 8
- L8: (8) 7 same 4
- L11: (2892) 2 near 2 5
- L12: (44) 11 same 4
- L13: (2) 12 same 1
- L14: (14) 11 same 1
- L15: (8) 14 and 4
- L16: (14) 8 15

## Failed

## Saved

 (1) 09/949877 07381-KONINKLIJK DUURIPS ~

U	I	operator	Document	Issue P	From	Current	CurrentXN	Review	S	C	F	T	Y	Z	Image	Doc	P
1	<input type="checkbox"/>	Kohno, Yasuh	US 6180966	20010.1	Trench gate type semiconductor device with	257/173	257/174		<input type="checkbox"/>	US 618096							
2	<input type="checkbox"/>	Iijima, Tadas	US 5803053	19890.4	Semiconductor device	257/751	257/764		<input type="checkbox"/>	US 580305							
3	<input type="checkbox"/>	Hayakawa, Y	US 2004008	20040.2	Semiconductor device and method for manuf.	257/412			<input type="checkbox"/>	US 200400							
4	<input type="checkbox"/>	Arai, Tatsuya	US 2004007	20040.3	Semiconductor device and method for manuf.	257/66			<input type="checkbox"/>	US 200400							
5	<input type="checkbox"/>	Ellison, Alexa	US 2003007	20030.2	High resistivity silicon carbide single crystal	117/88	117/105		<input type="checkbox"/>	US 200300							
6	<input type="checkbox"/>	Zhang, Hongy	US 2001002	20010.1	Semiconductor device and method of manuf.	257/59	257/347		<input type="checkbox"/>	US 200100							
7	<input type="checkbox"/>	Zhang, Hongy	US 6225645	20010.2	Semiconductor device and method of manuf.	257/59	257/347		<input type="checkbox"/>	US 622564							
8	<input type="checkbox"/>	Yamazaki, Sh	US 5988286	19990.1	Semiconductor device and a method of manu	257/85	257/347		<input type="checkbox"/>	US 598828							
9	<input type="checkbox"/>	Zhang, Hongy	US 5922125	19990.1	Semiconductor device and method of manuf	117/9	117/10		<input type="checkbox"/>	US 592212							
10	<input type="checkbox"/>	Matsubara, Y	US 5587580	19981.1	Test piece for X-ray inspection	257/48	257/384		<input type="checkbox"/>	US 558758							

/for: [ ] [ ] [ ]

Ready

Browsing | Download | Clear

Dots: USPTA:US\_PCT:EP:EPD\_EPO:DE:DEVENT:IDM:TDB

Default operator: OR  Plurals  Highlight all occurrences initially

8.15

June 2004

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